Supporting Information

Transmission electron microscopy (TEM) was carried out on a FEI Titan-Transmission Electron Microscope at 80 kV. The TEM specimen of gelatin/graphene oxide (GO) nanocomposite was sectioned by using the Focused Ion Beam with Cobra ion column system.

**Figure S1.** TEM image of gelatin/GO (1 wt%) nanocomposite showing single GO nanosheets.